TI-RSLKMAX

Texas Instruments Robotics System Learning Kit





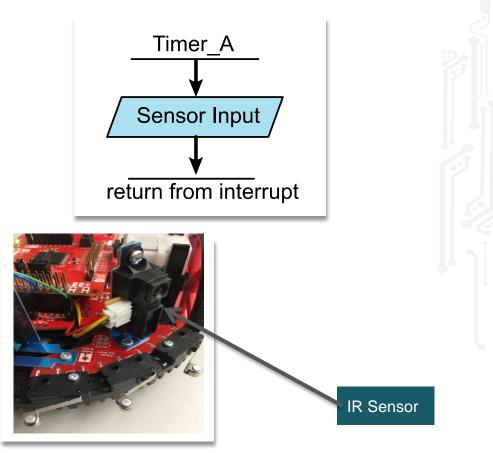
Module 15

Lecture: Data Acquisition Systems - Theory

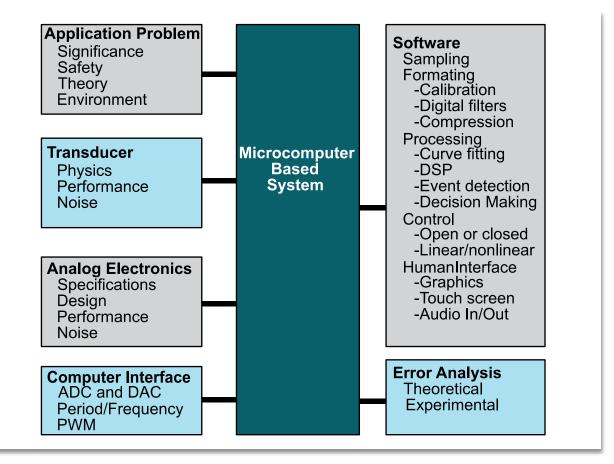
Data Acquisition Systems

You will learn in this module

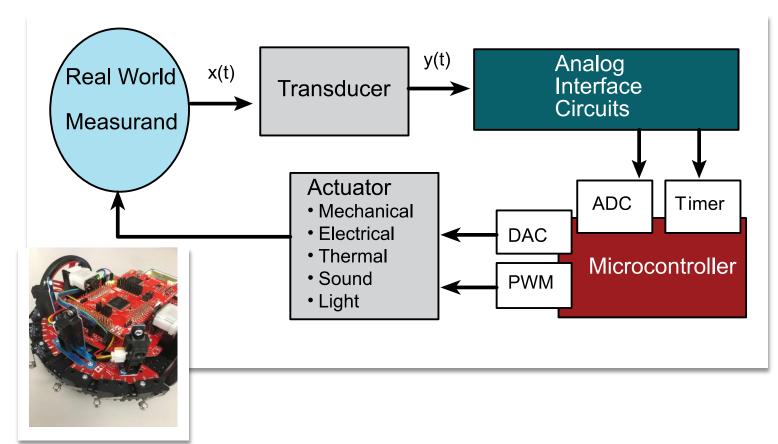
- Signals & Sampling
 - ADC, DAC
 - Range, resolution, precision
 - Successive approximation
- MSP432
 - Software driver
 - Spectrum Analyzer
 - Central Limit Theorem



Data Acquisition Systems



A Control System includes a Data Acquisition System



Sampling: conversion from analog to digital

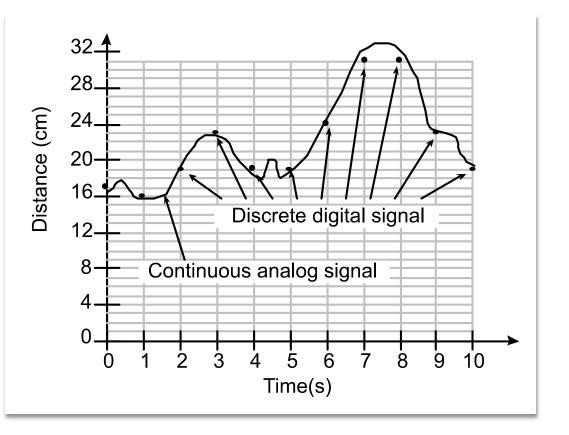
Amplitude

- Range
- Resolution
- Precision

Time domain

- Sampling rate, f_s
 - 0 to $\frac{1}{2} f_{s}$
- Number of samples
 - Buffer size N
- Frequency resolution

• f_s/N



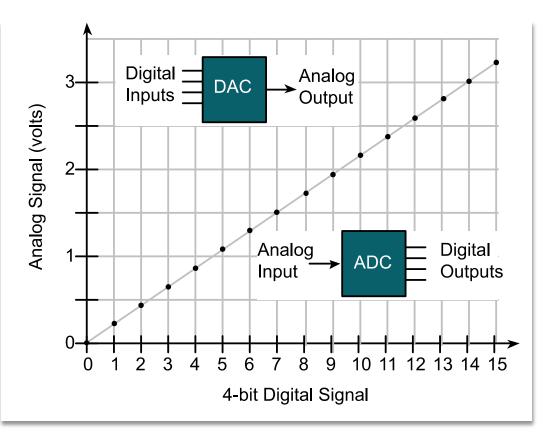
DAC versus ADC

DAC

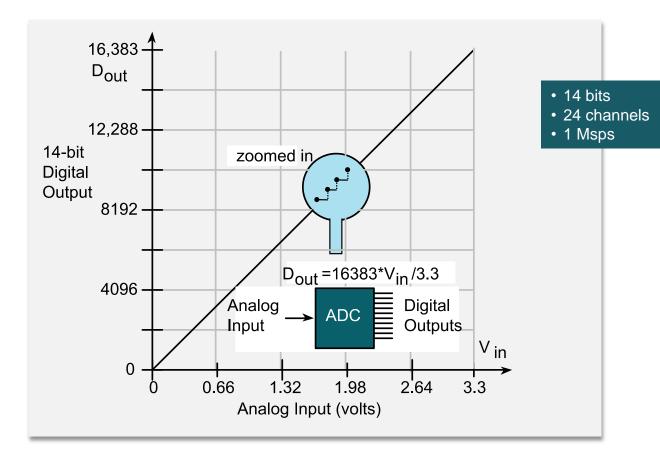
- Digital to Analog
- uC output
- Signal generation

ADC

- Analog to Digital
- uC input
- Measurements







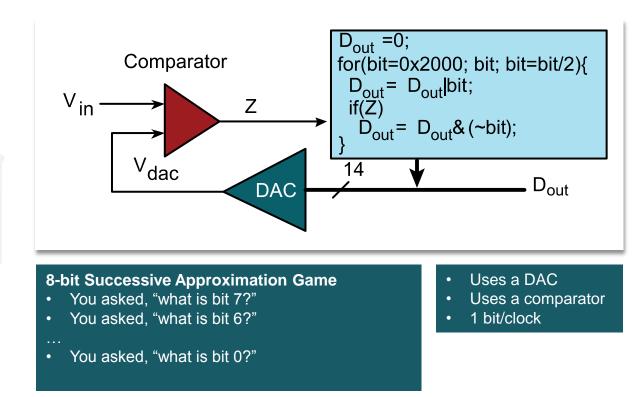
Successive Approximation

8-bit Successive Approximation Game

- I pick a number from 0 to 255
- You can guess
- I will respond high or low (same)
- How many guesses will it take you?

What is your first guess?

Successive Approximation – How it works



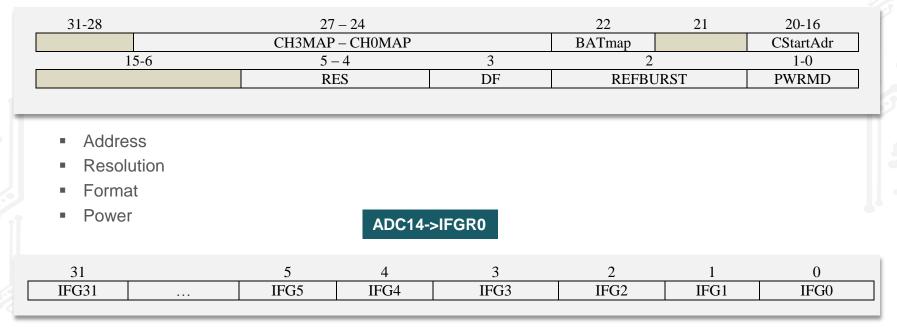
Good information https://e2e.ti.com/blogs/b/msp430blog/archive/2016/05/10/how-to-leverage-the-flexibility-of-an-integrated-adc-in-an-mcu-for-your-design-to-outshine-your-competitor-part-1

ADC14->CTL0

31-30	29-27	26	25	24-22	21-19	18-17	16
PDIV	SHSx	SHP	ISSH	DIVx	SSELx	CONSx	BUSY
15-12	11-8	7	6-5	4	3-2	1	0
SHT1x	SHT0x	MSC		ON		ENC	SC

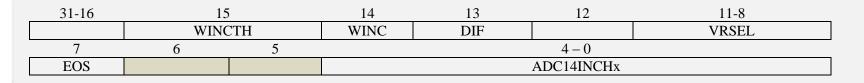
- Clock (speed/power)
- Sample and hold (noise)
- Sequence or single channel
- Reference (range)
- Enable
- Start sample

ADC14->CTL1



Conversion complete

ADC->MCTL[n]



- Comparator
- Differential/single
- Reference
- Channel

ADC14 Software Conversion

- 1. Wait for BUSY to be zero
- 2. Start conversion
- 3. Wait for completion
- 4. Read result

```
uint32_t ADC_In6(void) {
  while(ADC14->CTL0&0x00010000){};
  ADC14->CTL0 |= 0x00000001;
  while((ADC14->IFGR0&0x01) == 0){};
  return ADC14->MEM[0];
```

Periodic Interrupt and Mailbox

- 1. Sample ADC
- 2. Run digital filter
- 3. Save in global
- 4. Set semaphore

```
void SysTick_Handler(void) {
    uint32_t RawADC;
    P1OUT ^= 0x01;
    P1OUT ^= 0x01;
    RawADC = ADC_In6();
    ADCvalue = LPF_Calc(RawADC);
    ADCflag = 1; // semaphore
    P1OUT ^= 0x01;
}
```

9us



Analog to Digital Converter

- Successive Approximation
- Range
- Resolution
- Precision

Software

- Initialization
- Mailbox

 $100 \sum_{n=1}^{n} |x_{ti} - x_{mi}|$ **X**_{tmax} n *i*=0





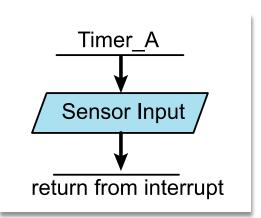
Module 15

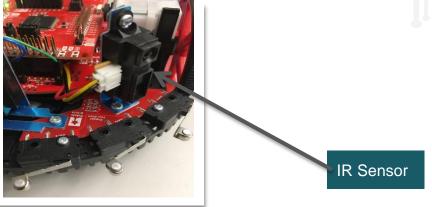
Lecture: Data Acquisition Systems – Performance Measurements

Data Acquisition Systems

You will learn in this module

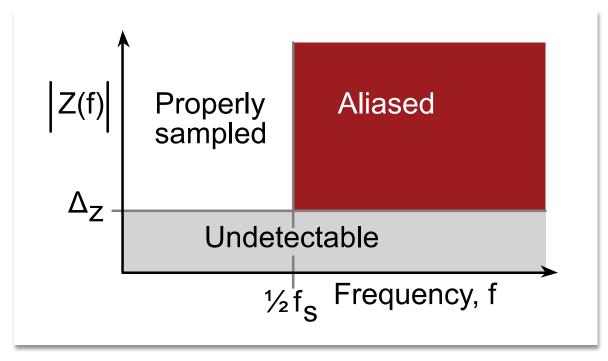
- Analog to Digital Converter
 - Sampling, Nyquist Theorem
 - **Digital filtering** .
- Noise and statistics
 - **Probability Mass Function** •
 - Spectrum Analyzer •
 - **Central Limit Theorem**
- Data Acquisition Systems
 - Range, resolution, precision
 - Calibration
 - Accuracy





18

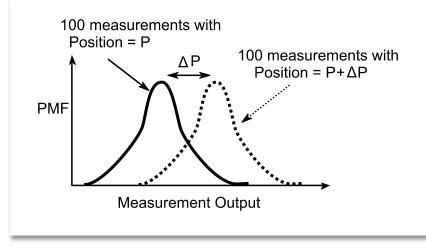




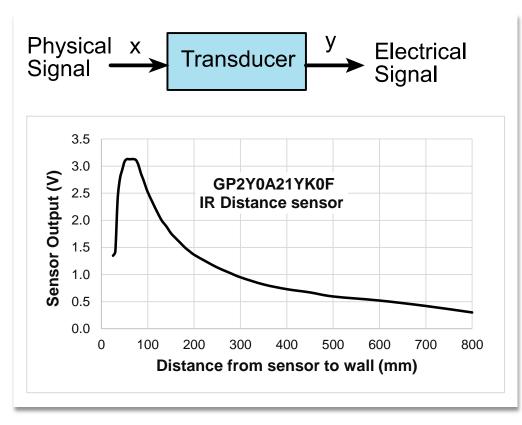
The **Nyquist Theorem** states that if the signal is sampled with a frequency of f_s , then the digital samples only contain frequency components from 0 to $\frac{1}{2} f_s$.



- Probability Mass Function (PMF)
- Average (µ = mean)
- Standard deviation (σ = sigma)
- Range (max-min)
- Coefficient of variation, $CV = \sigma/\mu$
- Precision log₂(μ/σ)
- Resolution, Δ



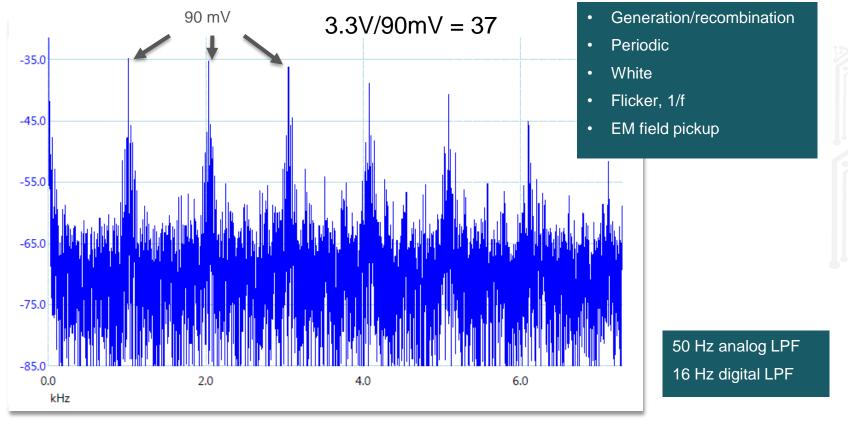






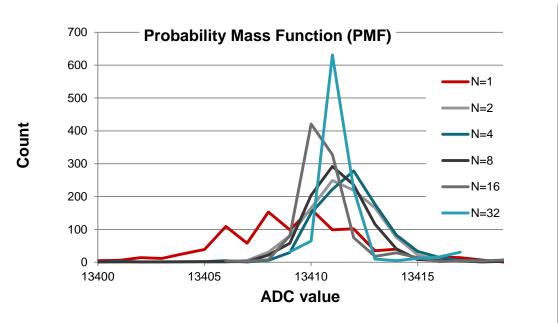
- Nonmontonic
- Hyperbolic
- Noisy

GP2Y0A21YK0F IR distance sensors are noisy



 $dB_{FS} = 20 \log_{10}(V/3.3)$

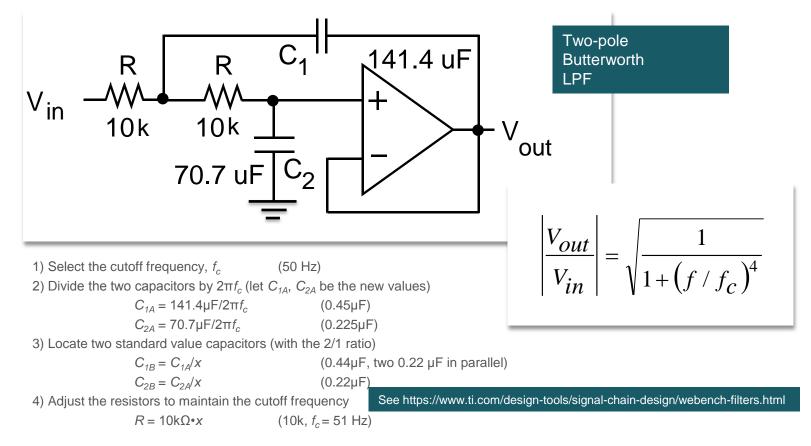
Probability Mass Function (PMF)



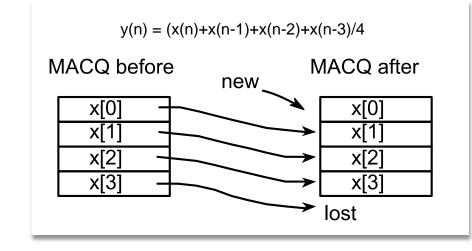
CLT states that as independent random variables are added, their sum tends toward a Normal distribution.

- Constant input
- Average of last N samples
- $f_s = 1000 \text{ Hz}$

Analog Low Pass Filter to remove Aliasing



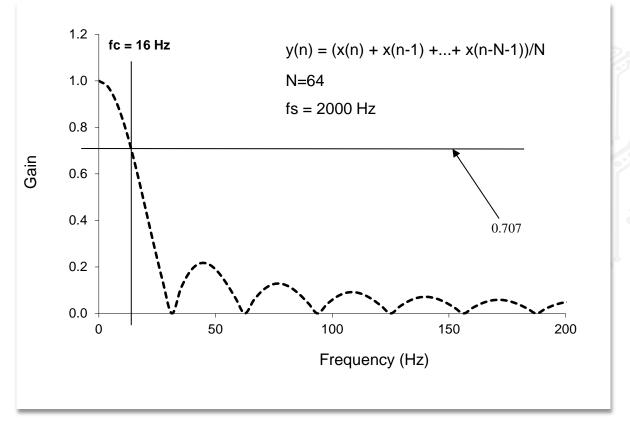
Digital Filtering



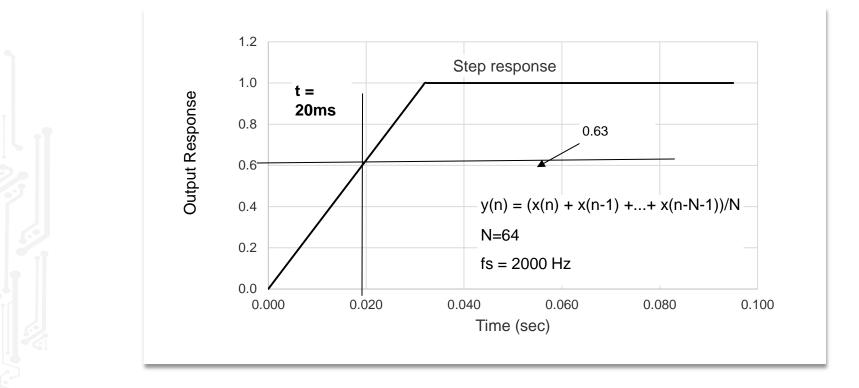
25 | Data Acquisition Systems – Performance Measurements

Averaging Low Pass Filters

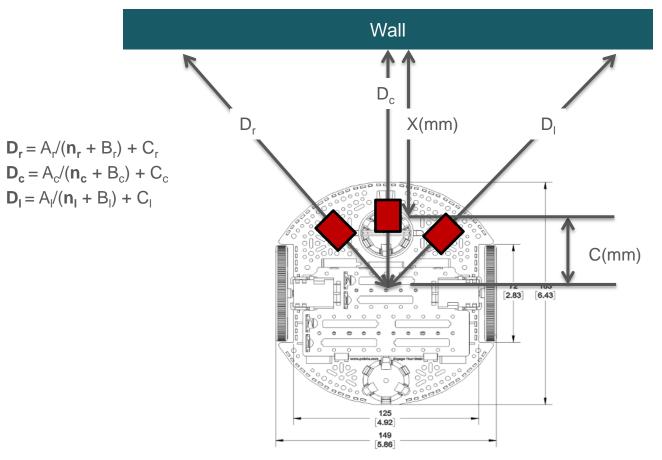
- Linear Filter
- Finite Impulse Response
- Low pass



Averaging Low Pass Filters



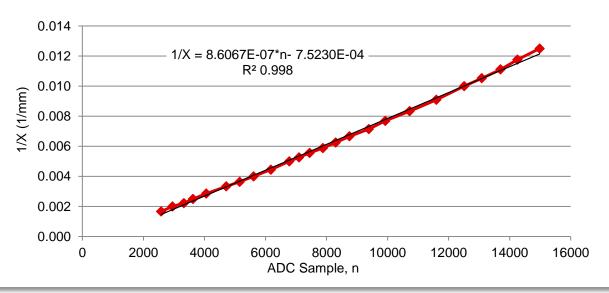
Distance to wall





- Distance, X, from the sensor to wall, 80 to 400mm
- ADC value, n
- Linear fit 1/X versus n
- Solve for X = A/(n+B)
- Add distance to central point, D = A/(n+B)+C







Analog to Digital Converter

Noise

Sampling

- Nyquist Theorem, Aliasing
- Central Limit Theorem

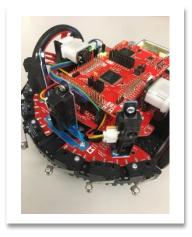
Filters

- Analog LPF
- Digital LPF

Data Acquisition Systems

- Calibration
- Accuracy

$$\frac{100}{n} \sum_{i=0}^{n} \frac{\left| x_{ti} - x_{mi} \right|}{x_{tmax}}$$





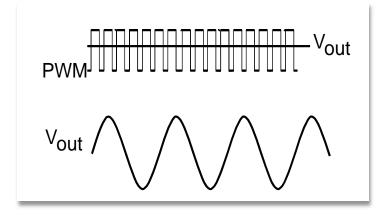
Module 15

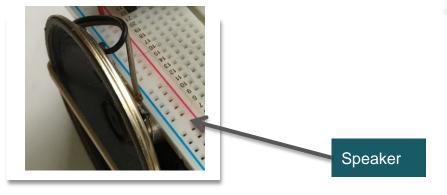
Lecture: Data Acquisition Systems – Sound generation

Data Acquisition Systems

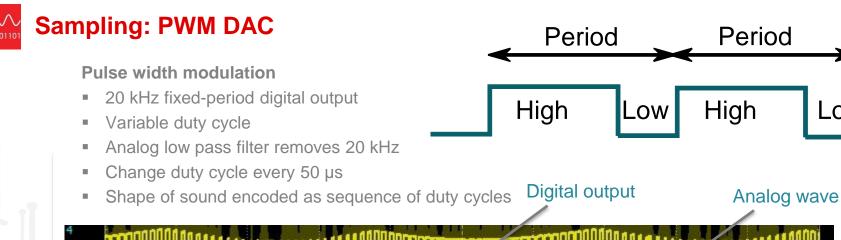
You will learn in this module

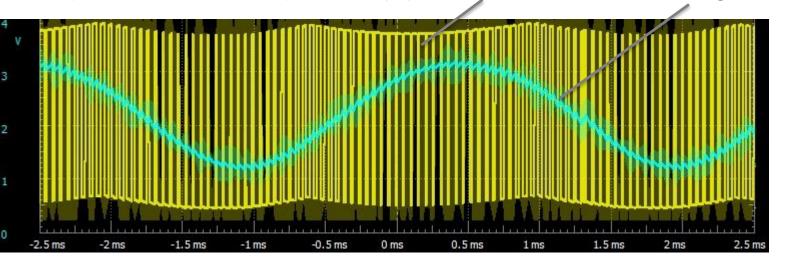
- Signals & Sampling
 - PWM, DAC
 - Range, resolution, precision
- Sound
 - Transducer
 - Analog Circuit
 - Sampling
 - Filtering





\sim Speaker generates sound Compression wave in both time and space Electromagnet Permanent 2 magnet Diaphragm Ear Speaker voltages Pitch = 1/T



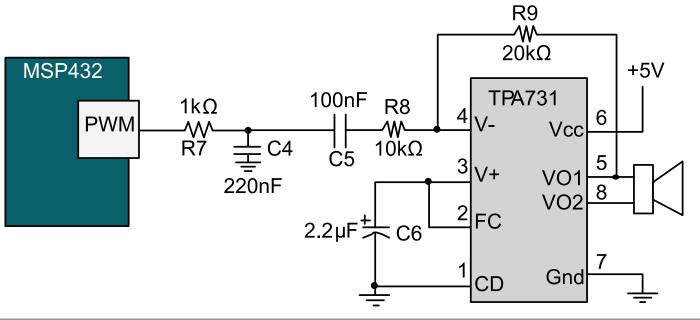


Low

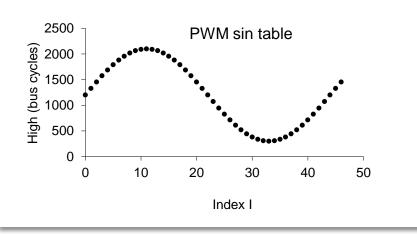
Interface between microcontroller and speaker

LPF to reject PWM frequency HPF to reject DC from PWM DAC Provide power to speaker TPA731 adds DC offset of 2.5V Gain of 4

LPF cutoff = $1/(2\pi C4R7) = 723Hz$ HPF cutoff = $1/(2\pi C5R8) = 159Hz$ C6 creates DC offset of 2.5V Gain=2*R9/R8 = 4



Software to generate PWM outputs



$$f_{PWM} = 48 \text{ MHz}/2424 = 19.8 \text{ kHz}$$

 $f_{sound} = 48 \text{ MHz}/(2424*45) = 440 \text{ Hz}$

Dutycycle =	High	High	
Dutycycle –	High + Low	Period	

```
#define Period 2424
const uint16_t wave440[45] = {
    1212,1339,1463,1583,1695,1798,1890,1968,2032,2079,2110,
    2123,2119,2097,2058,2002,1931,1846,1748,1640,1524,1402,
    1276,1148,1022,900,784,676,578,493,422,366,
    327,305,301,314,345,392,456,534,626,729,
    841,961,1085};
```

Software to generate PWM outputs

```
uint32_t startTime;
void SysTick_Wait2(uint32_t delay){
  volatile uint32_t elapsedTime;
  do{
    elapsedTime = (startTime-SysTick->VAL)&0x00FFFFFF;
  }
  while(elapsedTime <= delay);
  startTime = SysTick->VAL;
}
```

```
while(1) {
    High = wave440[i];
    Low = Period-High;
    SysTick_Wait2(Low);
    P3->OUT |= 0x40; // P3.6 high
    SysTick_Wait2(High);
    P4->OUT &= ~0x40; // P3.6 low
    i = (i+1)%45;
}
```

Dutycycle =	High	High
	High + Low	Period



DAC Precision

- Number of different duty cycles
- 48MHz/20kHz = 2400 alternative ≈ 11 bits
 DAC Range
- 0 to 3.3V

DAC Resolution

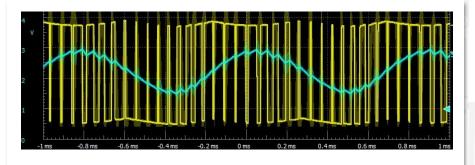
- 3.3V/2400
- Limited by noise and LPF cutoff
- Use spectrum analyzer to measure SNR

DAC Speed

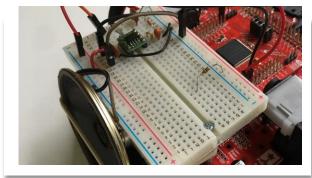
- Set by PWM period
- New duty cycle every 50 µs

Sound

- Loudness set by power to speaker
- Pitch set by size of duty cycle array
- Voice set by shape duty cycles in array
- Duration
- Envelope (time varying amplitude)



$f_{PWM} = 48 \text{ MHz}/2424 = 19.8 \text{ kHz}$ $f_{sound} = 48 \text{ MHz}/(2424^*45) = 440 \text{ Hz}$





Module 15

Lecture: Data Acquisition Systems - Sound recording

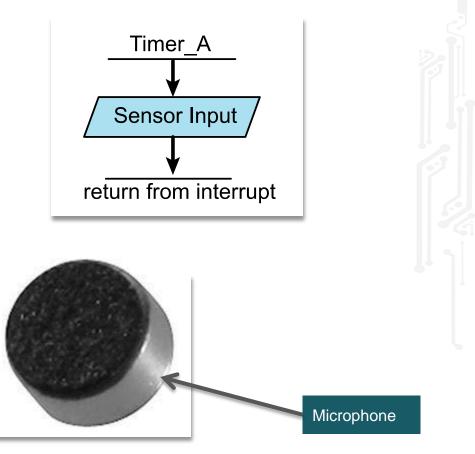
Data Acquisition Systems

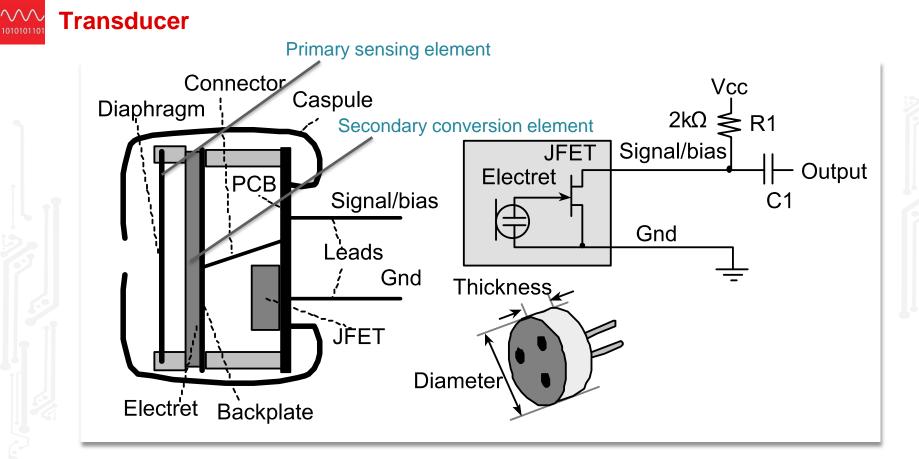
You will learn in this module

- Signals & Sampling
 - ADC, DAC
 - Range, resolution, precision
 - Successive approximation
- Sound

 $\Lambda \Lambda \Lambda$

- Transducer
- Analog Circuit
- Sampling
- Filtering
- Pitch Recognition

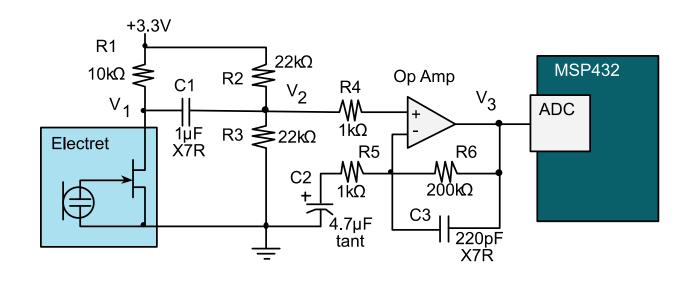




Interface between microphone and microcontroller

- Provide power to microphone
- HPF to reject DC
- Add DC offset of 1.65V
- Gain of 100
- LPF to prevent aliasing

Gain=1+R6/R5 = 201 HPF cutoff = $1/(2\pi C1(R2||R3)=14Hz$ LPF cutoff = $1/(2\pi C3R6)=3600Hz$



\sim

Sampling: adaptive noise rejection

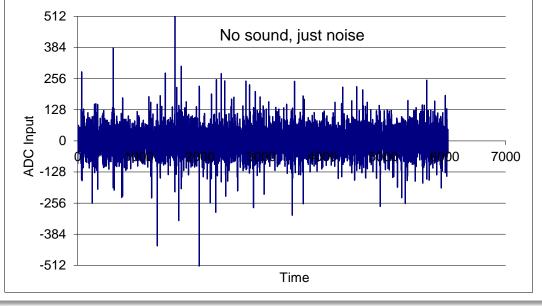
Noise

- Comes from microphone
- Very large
- Random
- Not correlated to itself

Signal

- Comes from sound pressure
- Highly correlated to itself





http://www.ti.com/lit/an/spra657/spra657.pdf

Cross correlation to see if signals are the same shape

Assumptions Sampled at f_{c} Data has zero average (just shape) Measured data x(n) is current sample x(n-1) is sample Δt ago x(n-2) is sample $2\Delta t$ ago Prerecorded data template y(n) is current sample y(n-1) is sample Δt ago y(n-2) is sample $2\Delta t$ ago Use cross correlation to see if same shape R_{XV} = +large means same shape $R_{xv} = 0$ means not same shape R_{xy} = -large means same, but inverted shape

$$f_s = 1/\Delta t$$
$$R_{xy}(m) = \lim_{N \to \infty} \frac{1}{N} \sum_{n=0}^{N-1} x(n) * y(n-m)$$

Autocorrelation

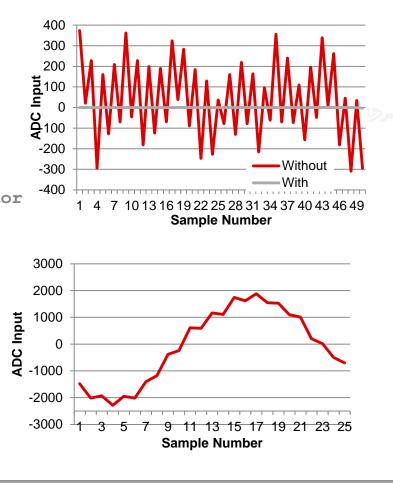
400 $f_s = 1/\Delta t$ 200 x(n) is current sample Input x(n-1) is sample Δt ago -200 x(n-2) is sample $2\Delta t$ ago ADC -400 -600 x(n-m) is sample $m \Delta t$ ago -800 -1000 $R_{xx}(m) = \lim_{N \to \infty} \frac{1}{N} \sum_{n=1}^{\infty} x(n) * x(n-m)$ $\begin{array}{c}
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 236$ 765543327 188 199 210 221 223 232 232 243 Sample Number Signal n = 0x(n) $Rxx2 \approx \frac{127}{128}Rxx2 + \frac{1}{128}x(n) * x(n-2)$ shifted by m x(n-m)

```
Noise reject filter
```

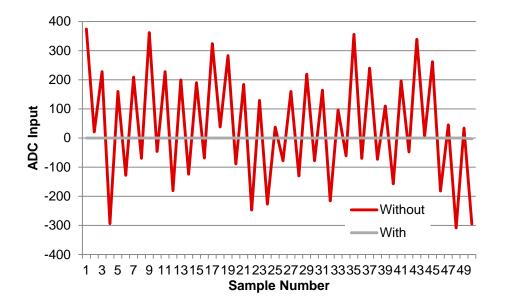
Autocorrelation

- Rxx2 = M-1 if signal correlated to itself
- Rxx2 = 0 if signal uncorrelated to itself

```
int32 t t0,t1,t2; // last 3 inputs/32
int32 t Rxx2; // autocorrelation factor
#define K 128 // how fast it responds
#define M 128
int32 t NoiseReject(int32 t x) {
 t2 = t1;
 t1 = t0;
 t0 = x/32;
 Rxx2 = ((K-1)*Rxx2 + t0*t2)/K;
 if (Rxx2 < -M) Rxx2 = -M;
 if(Rxx2 > M) Rxx2 = M;
 return (Rxx2*x)/M;
```

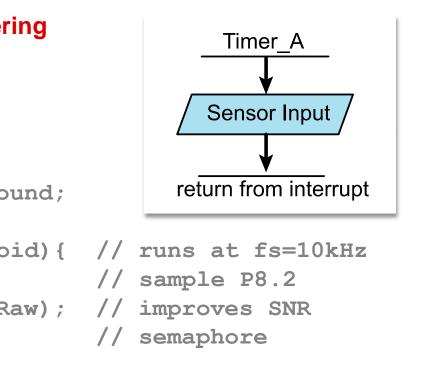


Results of noise suppression



$\wedge \wedge \wedge$ Data acquisition with digital filtering

```
volatile int32 t Raw,Sound;
#define DC 8192
void Program15 2 ISR(void) { // runs at fs=10kHz
 Raw = ADC In23()-DC; // sample P8.2
  Sound = NoiseReject(Raw); // improves SNR
  ADCflag = 1;
```



Use sound as command input to robot

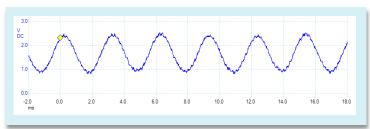
Initial training

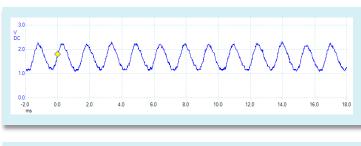
- A small number of sine-wave sounds
- Train by recording example of each
- Examples are the templates y(n)
 - Fixed sampling rate
 - Variable size to capture complete waves

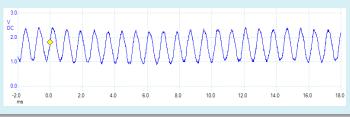
Use cross correlation to distinguish

- Calculate R_{XV} for each template
 - Use finite size buffers
 - Calculate max R_{xv} for various m
- Pitch recognition
 - Best match is largest R_{xy}
 - Above a threshold

Frequency Key Shifting (FSK)







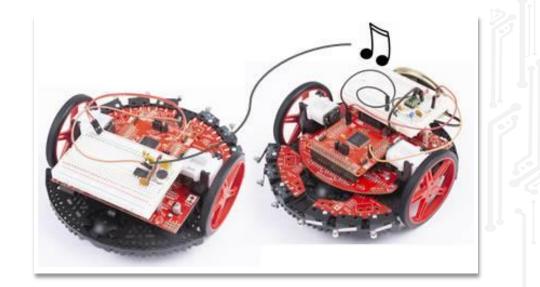


Sound recording

- Transducer
- Gain
- Analog filter

Digital processing

- Noise rejection using autocorrelation
 - Noise does not correlate with itself
 - Signal does correlate with itself
- Pitch recognition (FSK)
 - Training session
 - Cross correlation to find best match



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